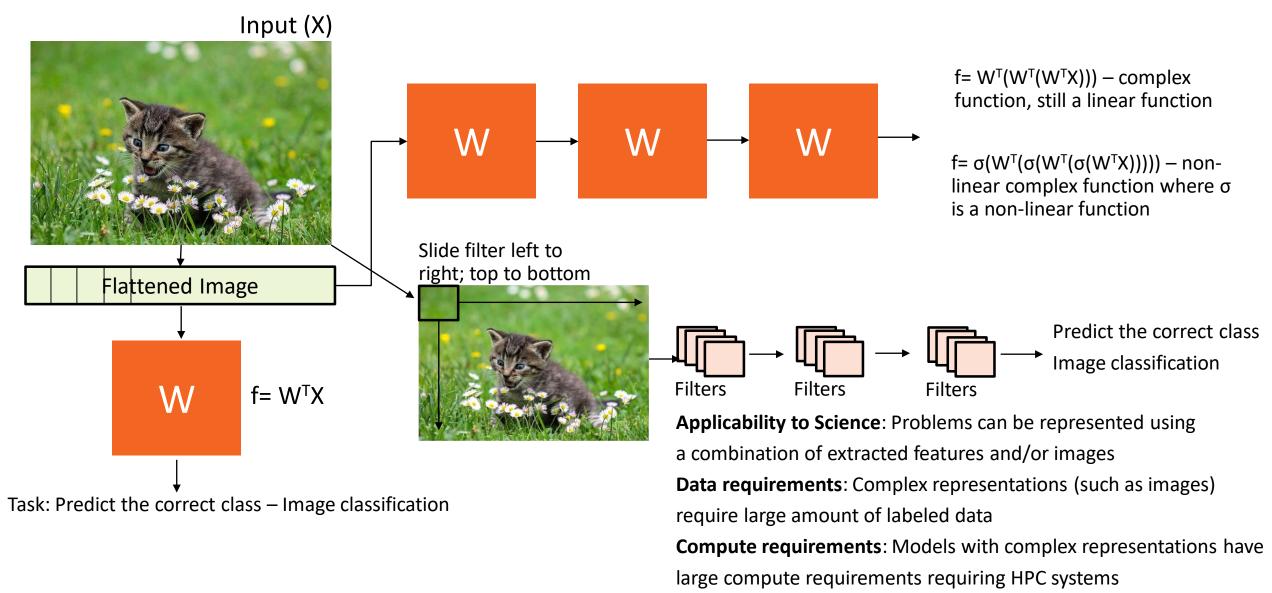


Bridging the Gap Between Deep Learning Algorithms and Systems

ABHINAV VISHNU

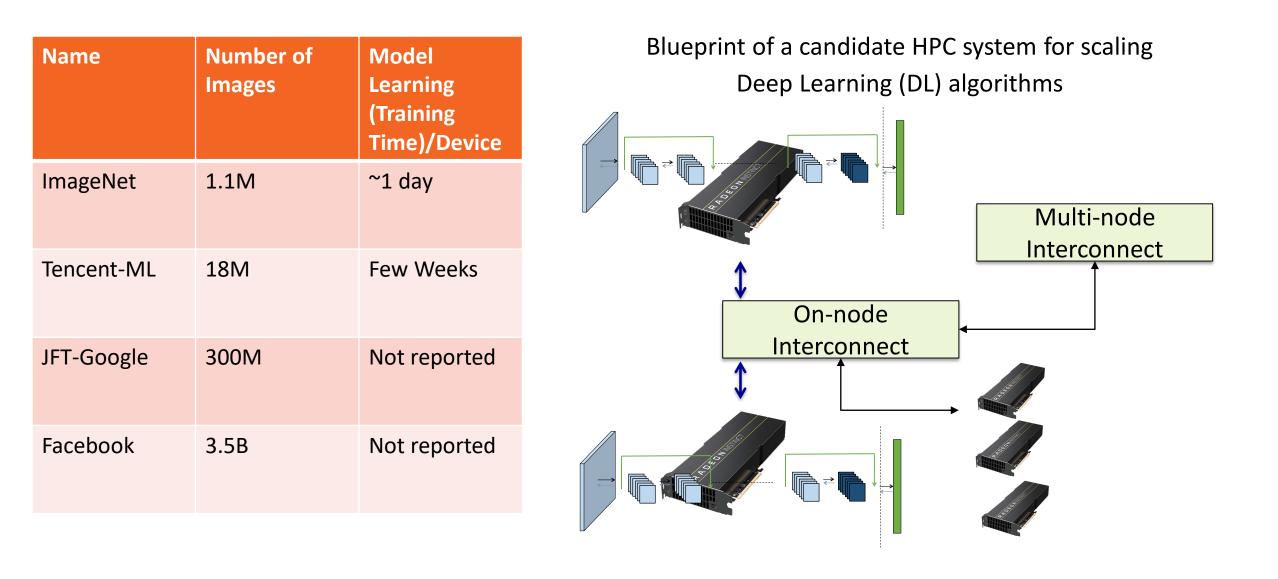
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A QUICK INTRODUCTION TO MACHINE LEARNING/DEEP LEARNING



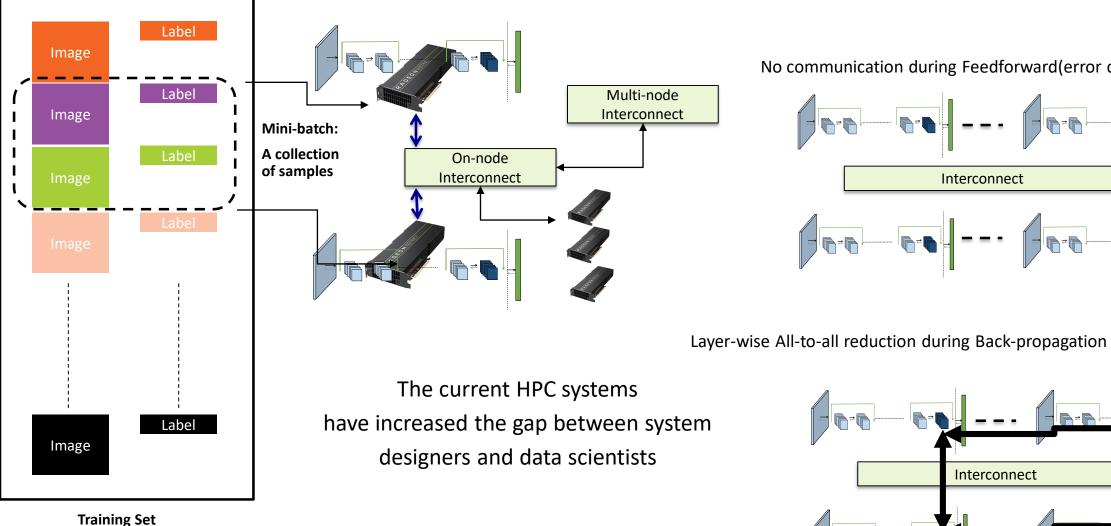
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TRENDS IN LABELED DATA AND MODEL LEARNING (TRAINING) TIME

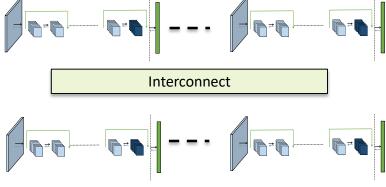


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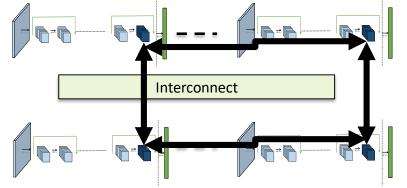
TRAINING DEEP LEARNING ALGORITHMS ON HPC SYSTEMS



No communication during Feedforward(error calculation) step



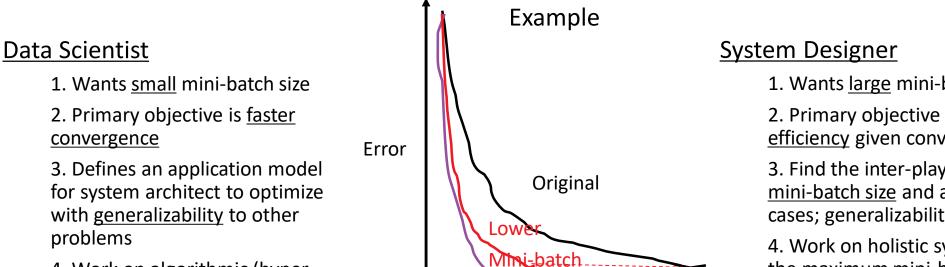
Layer-wise All-to-all reduction during Back-propagation (model learning) step



Popular Ring algorithm in DL algorithms

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THE MIS-MATCH BETWEEN SYSTEM DESIGNERS AND DATA SCIENTISTS



Hyper-parameter

optimizations

4. Work on algorithmic (hyperparameter) optimizations to improve accuracy

Epochs (number of passes over training set)

1. Wants large mini-batch size

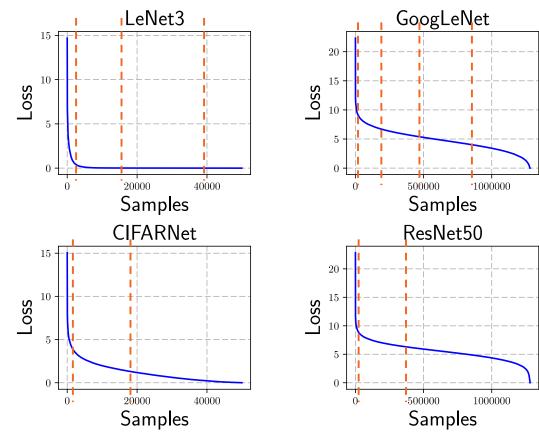
2. Primary objective is higher compute efficiency given convergence constraints

3. Find the inter-play between maximum mini-batch size and accuracy for the usecases; generalizability is not the focus

4. Work on holistic system design to enable the maximum mini-batch size

Machine Learning models and system architecture/software needs to be co-designed to help bridge the gap between data scientists and system designer

POTENTIAL SOLUTION: ADAPTIVE MINI-BATCHING



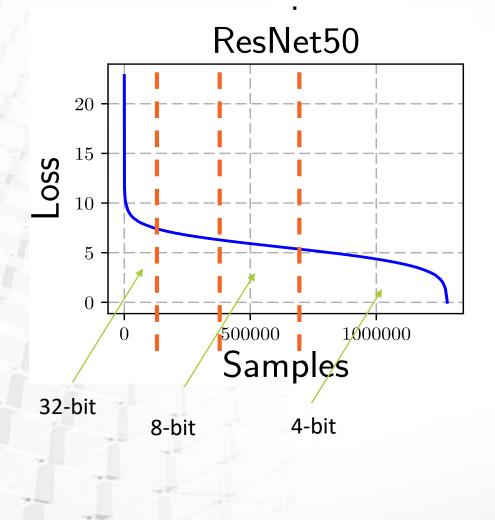
Three datasets, four networks

The error magnitude is computed by adding the error from samples in the training dataset

- However, only a handful of samples contribute to the error
 - For example consider ResNet50 (after one epoch) on the adjacent figure
- Few samples have very high error, most samples have low error
 - The error curve becomes flatter with epochs
 - Low error samples contribute less to model learning
- A combination of large and small mini-batches may be created by epoch-wise analysis of the error/loss. An example is shown on the left
- Communication overhead is also reduced with adaptive mini-batching

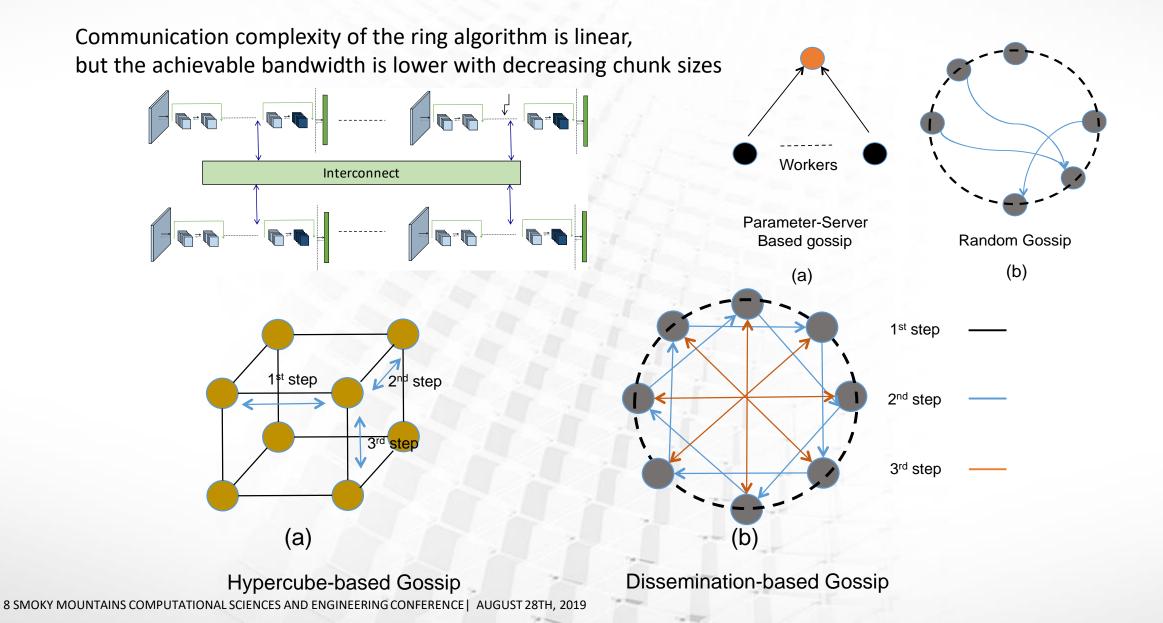
ACCELERATION USING ADAPTIVE PRECISION

- Split the samples in multiple buckets of different precision
- The buckets may be defined by sorting the samples using non-increasing error
 - Flatter loss implies lower number of bits may be enough to encode the weight updates in that bucket
 - Loss becomes flatter with increasing epochs
- Reset the precision if validation loss increases
 - Reduce the precision adaptively after the reset
 - Self-corrects the problems due to aggressive reduction in precision



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CONCLUSIONS

- Deep Learning (DL) algorithms are becoming popular as they leverage complex representations (such as raw input with images) in addition to extracted features
- ▲ HPC systems play an important role in reducing the time-to-solution for DL algorithms
- ▲ There is a widening gap in primary metrics of concern between a data scientist and a system designer
- We proposed approaches to bridge the gap by using adaptive mini-batching
 - For high error samples, use small mini-batches
 - For low error samples, use large mini-batches under the memory and compute constraints of the system
 - Proposed adaptive precision (high precision for high error samples) that matches well with the compute capabilities of today's systems
 - Proposed solution for addressing the limitations of all-to-all reduction by using reduced communication cardinality
- We hope to work with the scientific community to enhance these solutions and present results through publications and open source software

THANKS FOR LISTENING!! QUESTIONS?



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